## MOSFET - Power, N-Channel, SUPERFET ${ }^{\circledR}$ III, Easy-Drive <br> 650 V, 24 A, 125 m $\Omega$

## FCMT125N65S3

## General Description

SUPERFET III MOSFET is ON Semiconductor's brand-new high voltage super-junction (SJ) MOSFET family that is utilizing charge balance technology for outstanding low on-resistance and lower gate charge performance. This advanced technology is tailored to minimize conduction loss, provide superior switching performance, and withstand extreme dv/dt rate

Consequently, SUPERFET III MOSFET Easy-drive series helps manage EMI issues and allows for easier design implementation.

The Power88 package is an ultra-slim surface-mount package ( 1 mm high) with a low profile and small footprint $\left(8 \times 8 \mathrm{~mm}^{2}\right)$. SUPERFET III MOSFET in a Power88 package offers excellent switching performance due to lower parasitic source inductance and separated power and drive sources. Power88 offers Moisture Sensitivity Level 1 (MSL 1).

## Features

- $700 \mathrm{~V} @ \mathrm{~T}_{\mathrm{J}}=150^{\circ} \mathrm{C}$
- $\operatorname{Typ} \mathrm{R}_{\mathrm{DS}(\mathrm{on})}=100 \mathrm{~m} \Omega$
- Ultra Low Gate Charge (Typ. $\left.\mathrm{Q}_{\mathrm{g}}=49 \mathrm{nC}\right)$
- Low Effective Output Capacitance (Typ. Coss(eff.) $=406 \mathrm{pF})$
- $100 \%$ Avalanche Tested
- These Devices are $\mathrm{Pb}-$ Free and are RoHS Compliant


## Applications

- Telecom / Server Power Supplies
- Industrial Power Supplies
- UPS / Solar

ON Semiconductor ${ }^{\text {® }}$
www.onsemi.com

| $\mathbf{V}_{\text {DSS }}$ | $\mathbf{R}_{\text {DS(ON) }}$ MAX | $\mathbf{I}_{\mathrm{D}}$ MAX |
| :---: | :---: | :---: |
| 650 V | $125 \mathrm{~m} \Omega @ 10 \mathrm{~V}$ | 24 A |



N-CHANNEL MOSFET


MARKING DIAGRAM

|  |
| :--- | :--- |
| \$Y\&Z\&3\&K |
| FCMT |
| 125N65S3 |
|  |

= ON Semiconductor Logo
= Assembly Plant Code
= Data Code (Year \& Week)
= Lot
= Specific Device Code

ORDERING INFORMATION
See detailed ordering and shipping information on page 2 of this data sheet.

ABSOLUTE MAXIMUM RATINGS $\left(T_{C}=25^{\circ} \mathrm{C}\right.$, Unless otherwise noted)

| Symbol | Parameter |  | Value | Unit |
| :---: | :---: | :---: | :---: | :---: |
| $V_{\text {DSS }}$ | Drain to Source Voltage |  | 650 | V |
| $V_{G S S}$ | Gate to Source Voltage | DC | $\pm 30$ | V |
|  |  | AC ( $\mathrm{f}>1 \mathrm{~Hz}$ ) | $\pm 30$ | V |
| $\mathrm{I}_{\mathrm{D}}$ | Drain Current | Continuous ( $\mathrm{T}_{\mathrm{C}}=25^{\circ} \mathrm{C}$ ) | 24 | A |
|  |  | Continuous ( $\mathrm{T}_{\mathrm{C}}=100^{\circ} \mathrm{C}$ ) | 15 |  |
| IDM | Drain Current | Pulsed (Note 1) | 60 | A |
| $\mathrm{E}_{\text {AS }}$ | Single Pulsed Avalanche Energy (Note 2) |  | 115 | mJ |
| $\mathrm{I}_{\text {AS }}$ | Avalanche Current (Note 2) |  | 3.7 | A |
| $\mathrm{E}_{\text {AR }}$ | Repetitive Avalanche Energy (Note 1) |  | 1.81 | mJ |
| dv/dt | MOSFET dv/dt |  | 100 | V/ns |
|  | Peak Diode Recovery dv/dt (Note 3) |  | 20 |  |
| $\mathrm{P}_{\mathrm{D}}$ | Power Dissipation | ( $\mathrm{T}_{\mathrm{C}}=25^{\circ} \mathrm{C}$ ) | 181 | W |
|  |  | Derate Above $25^{\circ} \mathrm{C}$ | 1.45 | W/ ${ }^{\circ} \mathrm{C}$ |
| $\mathrm{T}_{\mathrm{J},} \mathrm{T}_{\text {STG }}$ | Operating and Storage Temperature Range |  | -55 to +150 | ${ }^{\circ} \mathrm{C}$ |
| $\mathrm{T}_{\mathrm{L}}$ | Maximum Lead Temperature for Soldering, 1/8" from Case for 5 s |  | 300 | ${ }^{\circ} \mathrm{C}$ |

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. Repetitive rating: pulse-width limited by maximum junction temperature.
2. $\mathrm{I}_{\mathrm{AS}}=3.7 \mathrm{~A}, \mathrm{R}_{\mathrm{G}}=25 \Omega$ starting $\mathrm{T}_{\mathrm{J}}=25^{\circ} \mathrm{C}$
3. $\mathrm{I}_{\mathrm{SD}} \leq 12 \mathrm{~A}, \mathrm{di} / \mathrm{dt} \leq 200 \mathrm{~A} / \mathrm{s}, \mathrm{V}_{\mathrm{DD}} \leq 400 \mathrm{~V}$, starting $\mathrm{T}_{\mathrm{J}}=25^{\circ} \mathrm{C}$

## THERMAL CHARACTERISTICS

| Symbol | Parameter | Value | Unit |
| :---: | :--- | :---: | :---: |
| $\mathrm{R}_{\text {өJC }}$ | Thermal Resistance, Junction to Case, Max. | 0.69 | $\mathrm{C} / \mathrm{W}$ |
| $\mathrm{R}_{\text {өJA }}$ | Thermal Resistance, Junction to Ambient, Max. (Note 4) | 45 |  |

4. Device on $1 \mathrm{in}^{2}$ pad 2 oz copper pad on $1.5 \times 1.5 \mathrm{in}$. board of FR-4 material.

ORDERING INFORMATION

| Device | Marking | Package | Reel Size | Tape Width | Quantity $^{\dagger}$ |
| :---: | :---: | :---: | :---: | :---: | :---: |
| FCMT125N65S3 | FCMT125N65S3 | PQFN8 | $13^{\prime \prime}$ | 13.3 mm | 3000 Units |

$\dagger$ For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

ELECTRICAL CHARACTERISTICS ( $\mathrm{T}_{\mathrm{C}}=25^{\circ} \mathrm{C}$ unless otherwise noted)

| Symbol | Parameter | Test Conditions | Min | Typ | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| OFF CHARACTERISTICS |  |  |  |  |  |  |
| $\mathrm{BV}_{\text {DSS }}$ | Drain to Source Breakdown Voltage | $\mathrm{V}_{\mathrm{GS}}=0 \mathrm{~V}, \mathrm{I}_{\mathrm{D}}=1 \mathrm{~mA}, \mathrm{~T}_{J}=25^{\circ} \mathrm{C}$ | 650 |  |  | V |
|  |  | $\mathrm{V}_{\mathrm{GS}}=0 \mathrm{~V}, \mathrm{I}_{\mathrm{D}}=1 \mathrm{~mA}, \mathrm{~T}_{J}=150^{\circ} \mathrm{C}$ | 700 |  |  | V |
| $\Delta \mathrm{BV}_{\text {DSs }} / \Delta \mathrm{T}_{\mathrm{J}}$ | Breakdown Voltage Temperature Coefficient | $\mathrm{I}_{\mathrm{D}}=1 \mathrm{~mA}$, Referenced to $25^{\circ} \mathrm{C}$ |  | 0.68 |  | V/ ${ }^{\circ} \mathrm{C}$ |
| $\mathrm{I}_{\text {DSS }}$ | Zero Gate Voltage Drain Current | $\mathrm{V}_{\mathrm{DS}}=650 \mathrm{~V}, \mathrm{~V}_{\mathrm{GS}}=0 \mathrm{~V}$ |  |  | 10 | $\mu \mathrm{A}$ |
|  |  | $\mathrm{V}_{\mathrm{DS}}=520 \mathrm{~V}, \mathrm{~T}_{\mathrm{C}}=125^{\circ} \mathrm{C}$ |  | 1.35 |  |  |
| IGSS | Gate to Body Leakage Current | $\mathrm{V}_{\mathrm{GS}}= \pm 30 \mathrm{~V}, \mathrm{~V}_{\mathrm{DS}}=0 \mathrm{~V}$ |  |  | $\pm 100$ | nA |

ON CHARACTERISTICS

| $\mathrm{V}_{\mathrm{GS}(\mathrm{th})}$ | Gate Threshold Voltage | $\mathrm{V}_{\mathrm{GS}}=\mathrm{V}_{\mathrm{DS}}, \mathrm{I}_{\mathrm{D}}=0.59 \mathrm{~mA}$ | 2.5 |  | 4.5 | V |
| :---: | :--- | :---: | :---: | :---: | :---: | :---: |
| $\mathrm{R}_{\mathrm{DS}(\mathrm{on})}$ | Static Drain to Source On Resistance | $\mathrm{V}_{\mathrm{GS}}=10 \mathrm{~V}, \mathrm{I}_{\mathrm{D}}=12 \mathrm{~A}$ |  | 100 | 125 | $\mathrm{~m} \Omega$ |
| $\mathrm{~g}_{\mathrm{FS}}$ | Forward Transconductance | $\mathrm{V}_{\mathrm{DS}}=20 \mathrm{~V}, \mathrm{I}_{\mathrm{D}}=12 \mathrm{~A}$ |  | 16 |  | S |

DYNAMIC CHARACTERISTICS

| $\mathrm{C}_{\text {iss }}$ | Input Capacitance | $\mathrm{V}_{\mathrm{DS}}=400 \mathrm{~V}, \mathrm{~V}_{\mathrm{GS}}=0 \mathrm{~V}, \mathrm{f}=1 \mathrm{MHz}$ | 1920 | pF |
| :---: | :---: | :---: | :---: | :---: |
| $\mathrm{C}_{\text {oss }}$ | Output Capacitance |  | 44 | pF |
| $\mathrm{C}_{\text {oss(eff.) }}$ | Effective Output Capacitance | $\mathrm{V}_{\mathrm{DS}}=0 \mathrm{~V}$ to $400 \mathrm{~V}, \mathrm{~V}_{\mathrm{GS}}=0 \mathrm{~V}$ | 406 | pF |
| $\mathrm{C}_{\text {oss(er.) }}$ | Energy Related Output Capacitance | $\mathrm{V}_{\mathrm{DS}}=0 \mathrm{~V}$ to $400 \mathrm{~V}, \mathrm{~V}_{\mathrm{GS}}=0 \mathrm{~V}$ | 63 | pF |
| $\mathrm{Q}_{\mathrm{g}(\text { tot) }}$ | Total Gate Charge at 10V |  | 49 | nC |
| $\mathrm{Q}_{\mathrm{gs}}$ | Gate to Source Gate Charge |  | 12 | nC |
| $\mathrm{Q}_{\mathrm{gd}}$ | Gate to Drain "Miller" Charge |  | 22 | nC |
| ESR | Equivalent Series Resistance | $\mathrm{f}=1 \mathrm{MHz}$ | 0.5 | $\Omega$ |

SWITCHING CHARACTERISTICS

| $t_{\text {d }}$ (on) | Turn-On Delay Time | $\begin{aligned} \mathrm{V}_{\mathrm{DD}}= & 400 \mathrm{~V}, \mathrm{I}_{\mathrm{D}}=12 \mathrm{~A}, \\ \mathrm{~V}_{\mathrm{GS}}= & 10 \mathrm{~V}, \mathrm{R}_{\mathrm{g}}=4.7 \Omega \\ & (\text { Note } 5) \end{aligned}$ | 22 | ns |
| :---: | :---: | :---: | :---: | :---: |
| $\mathrm{t}_{\mathrm{r}}$ | Turn-On Rise Time |  | 22 | ns |
| $t_{\text {d(off) }}$ | Turn-Off Delay Time |  | 60 | ns |
| $\mathrm{t}_{\mathrm{f}}$ | Turn-Off Fall Time |  | 5.8 | ns |

SOURCE-DRAIN DIODE CHARACTERISTICS

| Is | Maximum Continuous Source to Drain Diode Forward Current |  |  | 24 | A |
| :---: | :---: | :---: | :---: | :---: | :---: |
| ISM | Maximum Pulsed Source to Drain Diode Forward Current |  |  | 60 | A |
| $\mathrm{V}_{\text {SD }}$ | Source to Drain Diode Forward Voltage | $\mathrm{V}_{\mathrm{GS}}=0 \mathrm{~V}, \mathrm{I}_{\mathrm{SD}}=12 \mathrm{~A}$ |  | 1.2 | V |
| $\mathrm{t}_{\mathrm{rr}}$ | Reverse Recovery Time | $\mathrm{V}_{\mathrm{DD}}=400 \mathrm{~V}, \mathrm{I}_{\text {SD }}=12 \mathrm{~A}$, | 345 |  | ns |
| $\mathrm{Q}_{\mathrm{rr}}$ | Reverse Recovery Charge | $\mathrm{dl}_{\mathrm{F}} / \mathrm{dt}=100 \mathrm{~A} / \mu \mathrm{s}$ | 5.7 |  | $\mu \mathrm{C}$ |

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.
5. Essentially independent of operating temperature typical characteristics.

## TYPICAL PERFORMANCE CHARACTERISTICS



Figure 1. On-Region Characteristics


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage


Figure 5. Capacitance Characteristics


Figure 2. Transfer Characteristics


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature


Figure 6. Gate Charge Characteristics


Figure 7. Breakdown Voltage Variation vs. Temperature


Figure 9. Maximum Safe Operation Area


Figure 11. Eoss vs. Drain to Source Voltage


Figure 8. On-Resistance Variant vs. Temperature


Figure 10. Maximum Drain Current vs. Case Temperature

TYPICAL PERFORMANCE CHARACTERISTICS (Continued)


Figure 12. Transient Thermal Response Curve


Figure 13. Gate Charge Test Circuit \& Waveform


Figure 14. Resistive Switching Test Circuit \& Waveforms


Figure 15. Unclamped Inductive Switching Test Circuit \& Waveforms

## FCMT125N65S3



Figure 16. Peak Diode Recovery dv/dt Test Circuit \& Waveforms


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NOTES: UNLESS OTHERWISE SPECIFIED
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